

**AMENDMENTS TO THE ABSTRACT**

Please amend the Abstract as follows:

~~Disclosed is a~~ A method for performing scan test on a semiconductor integrated circuit including at least two blocks to be tested ~~each capable of performing active functions.~~ The method includes ~~at least the steps of~~ isolating each of the at least two blocks to be tested exclusively from further blocks; and supplying a plurality of scan clocks having different phases each to each of the at least two blocks, ~~in which the plurality of scan clocks each have the phase different from each other.~~ In addition, a semiconductor integrated circuit ~~for use in the method is provided including~~ includes at least two blocks to be tested ~~each capable of performing active functions,~~ an Core Wrapper Architecture isolation unit for isolating each of the at least two blocks to be tested exclusively from further blocks, and an input terminal for inputting a plurality of scan clocks each to each of the at least two blocks, ~~in which each of the at least two blocks is provided with a Core Wrapper Architecture as the isolation unit, and~~ a Wrapper register included in the Core Wrapper Architecture is configured to be supplied selectively with one of a scan clock and a system clock for the blocks.